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LED ARRAY



Lead-Free Parts

**LA73B-1/DBK.VA.VG-3-PF**

DATA SHEET

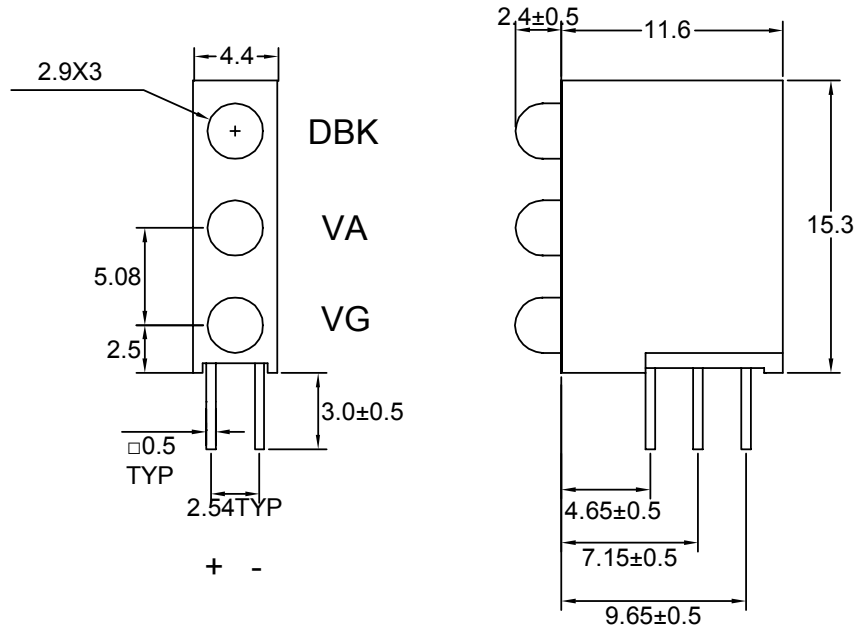
DOC. NO : QW0905-LA73B-1/DBK.VA.VG-3-PF

REV. : A

DATE : 12 - Jul. - 2005



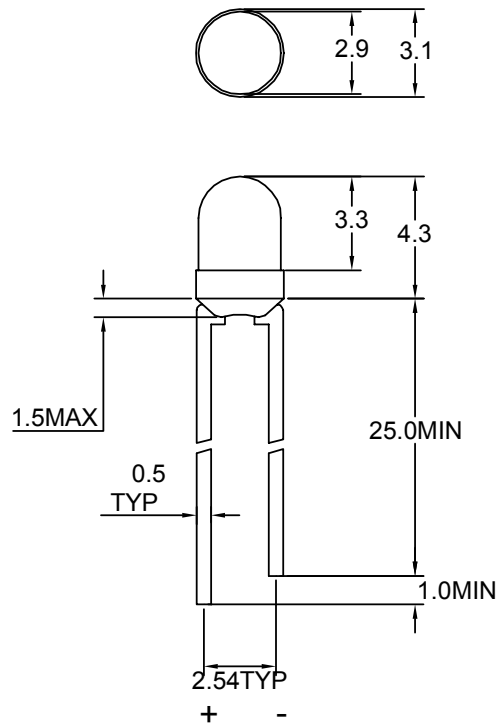
Package Dimensions



LDBK2643

LVA2641-1

LVG2641-1



Note : 1.All dimension are in millimeter tolerance is ±0.25mm unless otherwise noted.  
2.Specifications are subject to change without notice.



## Absolute Maximum Ratings at Ta=25

Parameter	Symbol	Ratings			UNIT
		DBK	VA	VG	
Forward Current	IF	30	30	30	mA
Peak Forward Current Duty 1/10@10KHz	IFP	100	60	120	mA
Power Dissipation	PD	120	75	100	mW
Reverse Current @5V	Ir	50	10	10	μ A
Electrostatic Discharge	ESD	150	2000		V
Operating Temperature	T <sub>opr</sub>	-20 ~ +80			
Storage Temperature	T <sub>stg</sub>	-30 ~ +100			
Soldering Temperature	T <sub>sol</sub>	Max 260 for 5 sec Max (2mm from body)			

## Typical Electrical &amp; Optical Characteristics (Ta=25 )

PART NO	MATERIAL	COLOR		Peak wave length Pnm	Dominant wave length Dnm	Spectral halfwidth nm	Forward voltage @20mA(V)			Luminous intensity @20mA(mcd)		Viewing angle 2 1/2 (deg)
		Emitted	Lens				Min.	Typ.	Max.	Min.	Typ.	
LA73B-1/DBK.VA.VG-3-PF	InGaN/SiC	Blue	Water Clear	----	470	30	---	3.5	4.0	350	700	30
	AlGaInP	Yellow	Orange Transparent	----	590	20	1.7	---	2.6	160	350	40
	GaP	Green	Green Transparent	565	----	30	1.7	---	2.6	65	120	40

Note : 1.The forward voltage data did not including  $\pm 0.1V$  testing tolerance.

2. The luminous intensity data did not including  $\pm 15\%$  testing tolerance.



### Typical Electro-Optical Characteristics Curve

DBK CHIP

Fig.1 Forward current vs. Forward Voltage

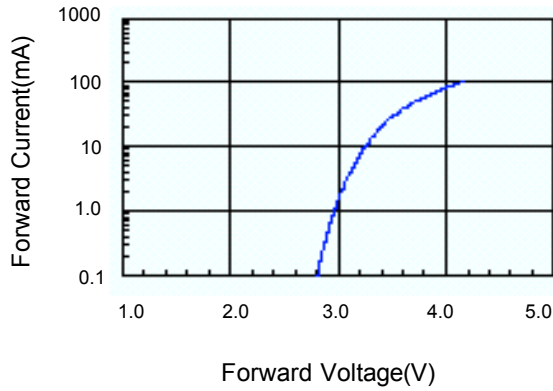


Fig.2 Relative Intensity vs. Forward Current

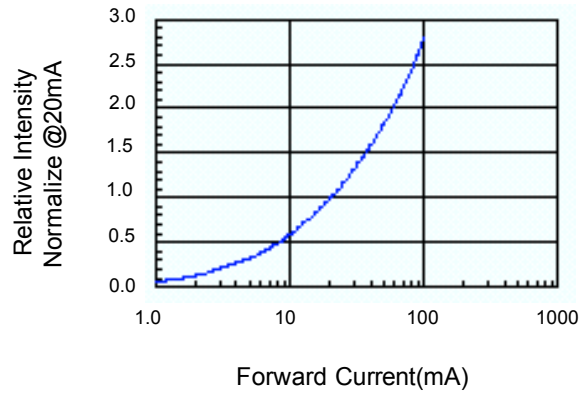


Fig.3 Forward Voltage vs. Temperature

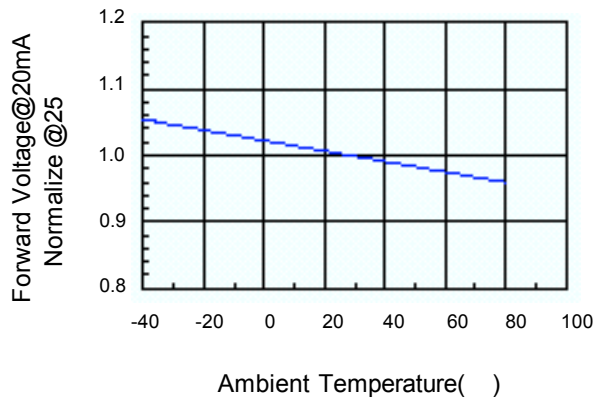


Fig.4 Relative Intensity vs. Temperature

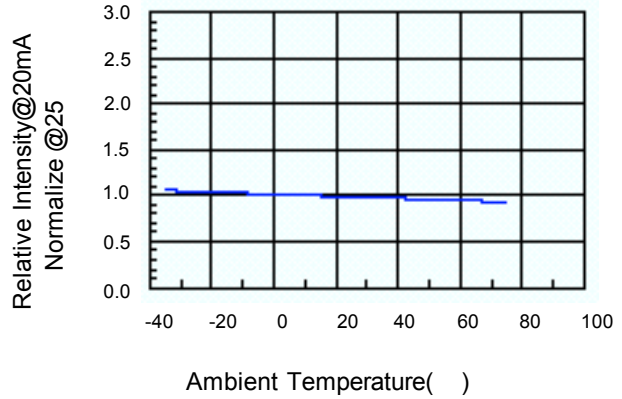
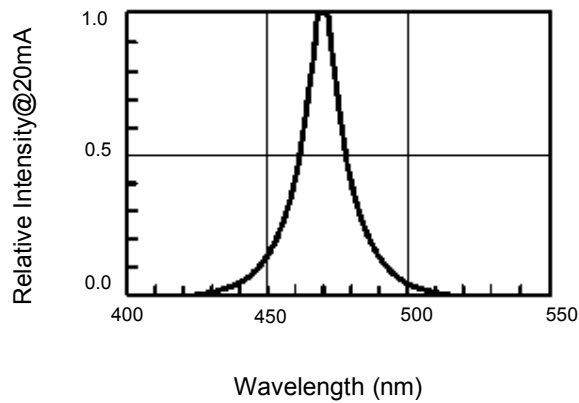


Fig.5 Relative Intensity vs. Wavelength





### Typical Electro-Optical Characteristics Curve

VY CHIP封橘膠

Fig.1 Forward current vs. Forward Voltage

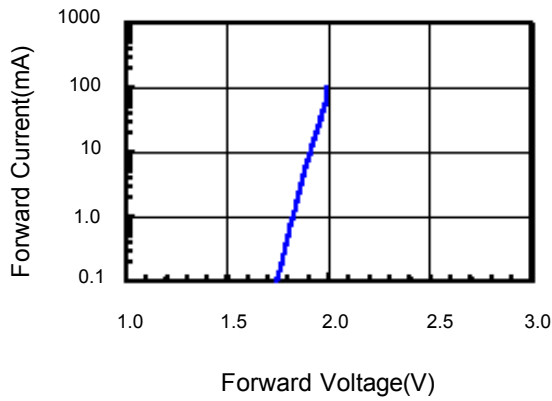


Fig.2 Relative Intensity vs. Forward Current

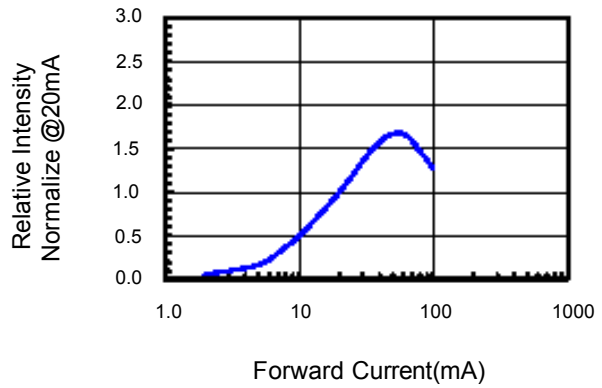


Fig.3 Forward Voltage vs. Temperature

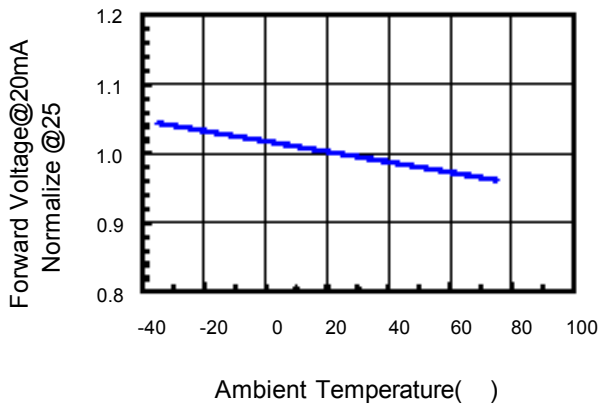


Fig.4 Relative Intensity vs. Temperature

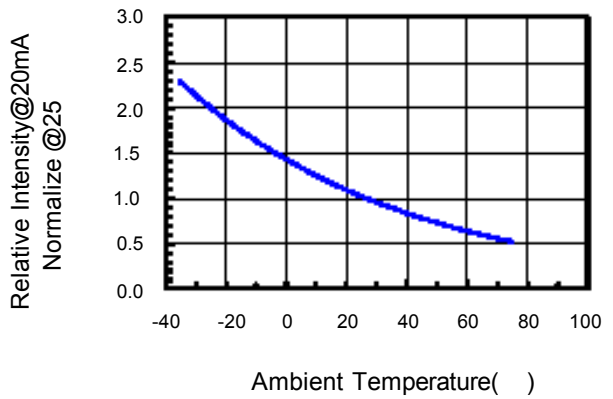
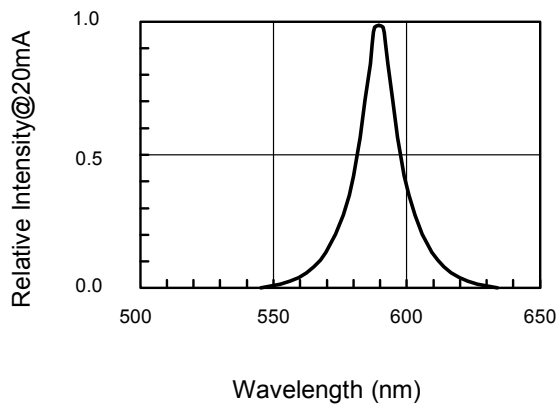


Fig.5 Relative Intensity vs. Wavelength



## Typical Electro-Optical Characteristics Curve

### VG CHIP

Fig.1 Forward current vs. Forward Voltage

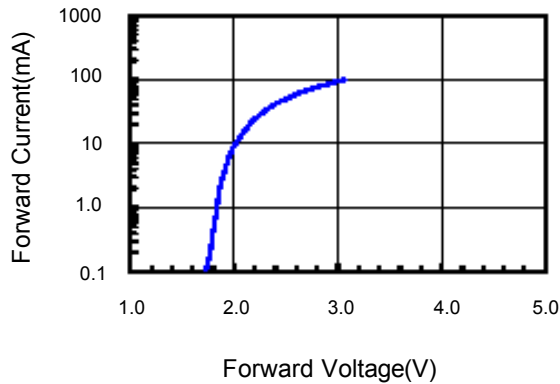


Fig.2 Relative Intensity vs. Forward Current

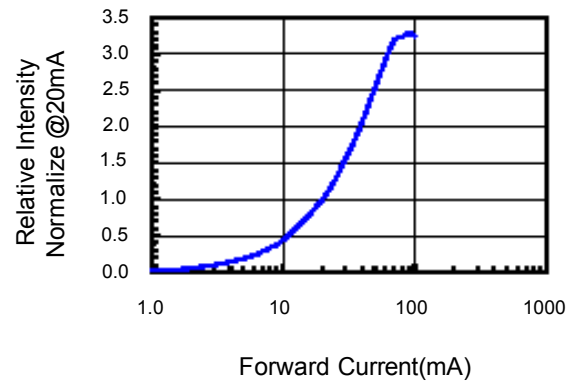


Fig.3 Forward Voltage vs. Temperature

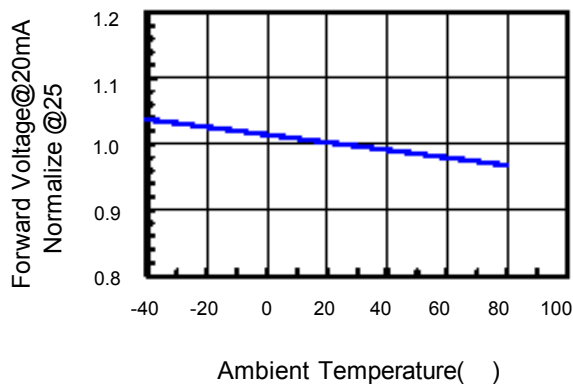


Fig.4 Relative Intensity vs. Temperature

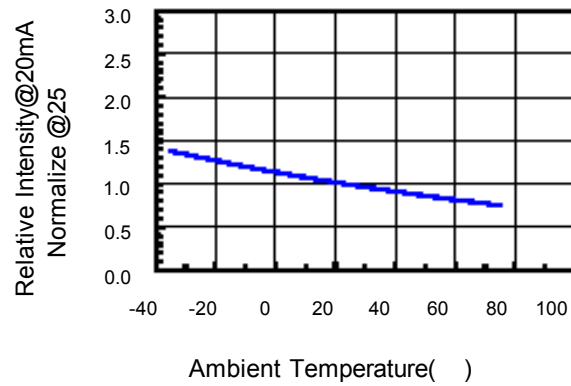
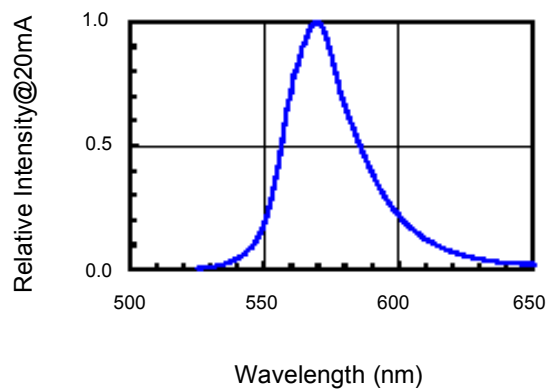


Fig.5 Relative Intensity vs. Wavelength





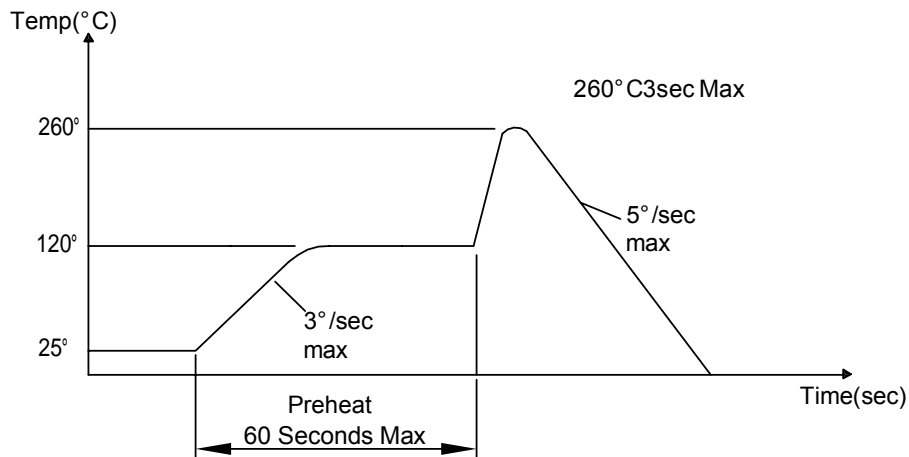
### Soldering Condition(Pb-Free)

#### 1.Iron:

Soldering Iron:30W Max  
Temperature 350° C Max  
Soldering Time:3 Seconds Max(One Time)  
Distance:2mm Min(From solder joint to case)

#### 2.Wave Soldering Profile

Dip Soldering  
Preheat: 120° C Max  
Preheat time: 60seconds Max  
Ramp-up  
3° C/sec(max)  
Ramp-Down:-5° C/sec(max)  
Solder Bath:260° C Max  
Dipping Time:3 seconds Max  
Distance:2mm Min(From solder joint to case)





Reliability Test:

Test Item	Test Condition	Description	Reference Standard
Operating Life Test	1.Under Room Temperature 2.If=20mA 3.t=1000 hrs (-24hrs, +72hrs)	This test is conducted for the purpose of determining the resistance of a part in electrical and thermal stressed.	MIL-STD-750: 1026 MIL-STD-883: 1005 JIS C 7021: B-1
High Temperature Storage Test	1.Ta=105 ±5 2.t=1000 hrs (-24hrs, +72hrs)	The purpose of this is the resistance of the device which is laid under condition of high temperature for hours.	MIL-STD-883:1008 JIS C 7021: B-10
Low Temperature Storage Test	1.Ta=-40 ±5 2.t=1000 hrs (-24hrs, +72hrs)	The purpose of this is the resistance of the device which is laid under condition of low temperature for hours.	JIS C 7021: B-12
High Temperature High Humidity Test	1.Ta=65 ±5 2.RH=90 %~95 % 3.t=240hrs ±2hrs	The purpose of this test is the resistance of the device under tropical for hours.	MIL-STD-202:103B JIS C 7021: B-11
Thermal Shock Test	1.Ta=105 ±5 & -40 ±5 (10min) (10min) 2.total 10 cycles	The purpose of this is the resistance of the device to sudden extreme changes in high and low temperature.	MIL-STD-202: 107D MIL-STD-750: 1051 MIL-STD-883: 1011
Solder Resistance Test	1.T.Sol=260 ±5 2.Dwell time= 10 ±1sec.	This test intended to determine the thermal characteristic resistance of the device to sudden exposures at extreme changes in temperature when soldering the lead wire.	MIL-STD-202: 210A MIL-STD-750: 2031 JIS C 7021: A-1
Solderability Test	1.T.Sol=230 ±5 2.Dwell time=5 ±1sec	This test intended to see soldering well performed or not.	MIL-STD-202: 208D MIL-STD-750: 2026 MIL-STD-883: 2003 JIS C 7021: A-2